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In-Situ Secondary Electron Yield Measurements for CESRTA: Update

W. Hartung, C. Dennett, V. Omanovic, Y. Li, T. Moore for the CESRTA Collaboration

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In-Situ Apparatus





TiNcoated sample



"Beam's eye" view



Material	Dates	Comments
TiN 1st pair	Jan 2010-Aug 2010	Samples from SLAC
AI	Aug 2010-Nov 2010	6061-T6 alloy
Amorphous C	Nov 2010-Jan 2011	Coating by CERN
Diamond-like C	Sep 2011-Nov 2011	Coating by KEK
TiN 2nd pair	Nov 2011-Mar 2012	Samples from SLAC
Cu	Mar 2012-Jul 2012	OFC 101
Stainless steel	Aug 2012-Oct 2012	316-series
TiN 2nd pair	Oct 2012-Jan 2013	Recondition after air exposure
AI	Jan 2013-	6063 alloy



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Beam conditioning: Peak SEY



Beam conditioning of SEY samples (center, inc. angle = 25°)



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Beam conditioning: Peak SEY



Conditioning vs reconditioning: TiN (center, inc. angle = 25°)



Conditioned Samples



SEY vs energy after conditioning (center, inc. angle = 25°)

Beam conditioning: SEY vs position



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Beam conditioning vs azimuth (inc. beam = 405 eV, 25°)



Work in progress/plans

- Monitor SEY vs time after conditioning, with samples in vacuum (done for Cu and reconditioned TiN)
- Remeasure SEY in Blue Room after exposure to air
- Interpret results so far; correct for systematic effects and connect measurements to SEY models, including SEY vs incident angle and SEY at low energy
- Near term: measure AI-6063, then new amorphous carbon samples